

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination YAMAGUCHI ET AL.	
		Examiner A. Sefer	Art Unit 2826	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,500,750	03-1996	Kanbe et al.	349/42
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 617310	09-1994	European	Kanbo et al	
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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